

Amended
begins at said output and returns to said output of said at least one logic element;

Amended
a capacitor being disposed within said closed loop circuit;

a resistor being disposed within said closed loop circuit; and

a crystal oscillator for high frequency being disposed within said closed loop circuit, said crystal oscillator being connected in series with said capacitor and in parallel with said resistor.

3. (Amended) A high-frequency oscillation circuit as claimed in claim 1, further comprising another capacitor being disposed externally to and in serial connection with said closed loop circuit.

4. A high-frequency oscillation circuit as claimed in claim 1, wherein said logic element includes a high-speed TTL or CMOS.

5. (Amended) A high-frequency oscillation circuit as claimed in claim 1, wherein said crystal oscillator of high frequency having a basic oscillation frequency of 30 MHz or more.

6. (Amended) A high-frequency oscillation circuit as claimed in claim 1,
said at least one logic element including a first logic element within said closed
loop circuit and another logic element external to said closed loop circuit.

7. (Amended) A high-frequency oscillation circuit as claimed in claim 6,
wherein said first logic element includes a high-speed CMOs.

8. (Amended) A high-frequency oscillation circuit as claimed in claim 6,
said crystal oscillator having a basic oscillation frequency of between 1 MHz to
500 MHz.

9. (Amended) A high-frequency oscillation circuit as claimed in claim 6,
wherein said crystal oscillator is used as a sensor element for chemical
measurement of a predetermined parameter.

Please add the following additional claims:--

10. A high-frequency oscillation circuit as claimed in claim 4, said
crystal oscillator having a basic oscillation frequency of 500 MHz or more.

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12. A high-frequency oscillation circuit as claimed in claim 1, further comprising another logic element being disposed externally to and in serial connection with said closed loop circuit.

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13. A measuring instrument for measuring a predetermined parameter, said measuring instrument comprising:

a closed loop, high frequency oscillation circuit including at least one logic element, said at least one logic element having an input and an output, wherein said closed loop circuit begins at said output and returns to said output of said at least one logic element;

a capacitor being disposed within said closed loop circuit;

a resistor being disposed within said closed loop circuit; and

a sensor for determining said predetermined parameter, wherein said sensor includes a crystal oscillator for high frequency being disposed within said closed loop circuit, said crystal oscillator being connected in series with said capacitor and in parallel with said resistor and having a natural oscillation frequency, a change in said natural oscillation frequency of said crystal oscillator being indicative of said predetermined parameter.

14. The measuring instrument for measuring said predetermined parameter according to claim 13, wherein said predetermined parameter

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Sub 1*

includes at least one of a weight parameter, a viscosity parameter, and a film thickness parameter.

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15. The measuring instrument for measuring said predetermined parameter according to claim 13, wherein said sensor is at least one of a weight sensor, a chemical sensor, a biosensor, a viscosity sensor, a film thickness meter, a gas sensor, a floating dust sensor, and an immunity sensor.

16. The measuring instrument for measuring said parameter according to claim 15, said crystal oscillator having a basic oscillation frequency of 500 MHz or more.

17. The measuring instrument for measuring said parameter according to claim 15, said crystal oscillator having a basic oscillation frequency of between 1 MHz and 500 MHz.

18. The measuring instrument for measuring said parameter according to claim 13, said at least one logic element including a first logic element within said closed loop circuit and another logic element external to said closed loop circuit.

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19. The measuring instrument for measuring said parameter according to claim 13, wherein said first logic element includes a high-speed CMOS.

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20. The measuring instrument for measuring said parameter according to claim 13, wherein said logic element includes a high-speed TTL or CMOS.--
